



**Key:** IEEE JNL = IEEE Journal or Magazine, IEE JNL = IEE Journal or Magazine, IEEE CNF = IEEE Conference, IEE CNF = IEE Conference, IEEE STD = IEEE Standard

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**Key:** IEEE JNL = IEEE Journal or Magazine, IEE JNL = IEE Journal or Magazine, IEEE CNF = IEEE Conference, IEE CNF = IEE Conference, IEEE STD = IEEE Standard

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| Ref # | Hits | Search Query   | DBs   | Default Operator | Plurals | Time Stamp       |
|-------|------|--|---|------------------|---------|------------------|
| L1    | 32   | (generate generated generation generating) and (compare comparator compared comparison comparing) and ((test TESTING TESTER TESTED) with ((integrated adj circuit) circuit semiconductor ic memory logic)) and (expect\$ with result) and (fail failure failed failing error erroneous) and "714"/\$.ccls. and (range window).ab.  | US-PGPUB;<br>USPAT;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR               | ON      | 2006/01/11 09:37 |
| L2    | 30   | ("5530370" "5390183" "6317700" "6219809" "6219809" "6510398" "6138259" "6369601" "6815943" "6850085" "5544175" "5732047" "5919270" "4779273" "4870346" "4807147" "5619588" "5907628" "5325360" "6760582" "6292830" "6349270" "5231598" "5398252" "6505274" "6401225" "6493841" "6195627" "6212491" "6188253" "5968194" "6360180" "5777932" "5260947" "5610925" "5701309" "6243841" "4583041" "4797886" "4827437" "4855969" "4860291" "4862071" "4888715" "4998025" "5381421" "5412662" "5422892" "5500862" "5590136").pn. and (range window) | USPAT   | OR               | ON      | 2006/01/11 09:37 |
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| S3 | 39 | ("5530370" "5390183" "6317700"<br>"6219809" "6219809" "6510398"<br>"6138259" "6369601" "6815943"<br>"6850085" "5544175" "5732047"<br>"5919270" "4779273" "4870346"<br>"4807147" "5619588" "5907628"<br>"5325360" "6760582" "6292830"<br>"6349270" "5231598" "5398252"<br>"6505274" "6401225" "6493841"<br>"6195627" "6212491" "6188253"<br>"5968194" "6360180" "5777932"<br>"5260947" "5610925" "5701309"<br>"6243841" "4583041" "4797886"<br>"4827437" "4855969" "4860291"<br>"4862071" "4888715" "4998025"<br>"5381421" "5412662" "5422892"<br>"5500862" "5590136").pn. and<br>(generat\$) and compar\$ and test\$               | USPAT | OR | ON | 2006/01/09 10:07 |
| S4 | 37 | ("5530370" "5390183" "6317700"<br>"6219809" "6219809" "6510398"<br>"6138259" "6369601" "6815943"<br>"6850085" "5544175" "5732047"<br>"5919270" "4779273" "4870346"<br>"4807147" "5619588" "5907628"<br>"5325360" "6760582" "6292830"<br>"6349270" "5231598" "5398252"<br>"6505274" "6401225" "6493841"<br>"6195627" "6212491" "6188253"<br>"5968194" "6360180" "5777932"<br>"5260947" "5610925" "5701309"<br>"6243841" "4583041" "4797886"<br>"4827437" "4855969" "4860291"<br>"4862071" "4888715" "4998025"<br>"5381421" "5412662" "5422892"<br>"5500862" "5590136").pn. and<br>(generat\$) and compar\$ and test\$<br>and result | USPAT | OR | ON | 2006/01/10 08:28 |

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| S5 | 62940 | (generate generated generation generating) and (compare comparator compared comparison comparing) and ((test TESTING TESTER TESTED) with ((integrated adj circuit) circuit semiconductor ic memory logic)) and result   | US-PGPUB;<br>USPAT;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2006/01/10 08:41 |
| S6 | 4691  | (generate generated generation generating) and (compare comparator compared comparison comparing) and ((test TESTING TESTER TESTED) with ((integrated adj circuit) circuit semiconductor ic memory logic)) and (expect\$ with result)   | US-PGPUB;<br>USPAT;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2006/01/10 08:42 |
| S7 | 3833  | (generate generated generation generating) and (compare comparator compared comparison comparing) and ((test TESTING TESTER TESTED) with ((integrated adj circuit) circuit semiconductor ic memory logic)) and (expect\$ with result) and (fail failure failed failing error erroneous)                                       | US-PGPUB;<br>USPAT;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2006/01/10 08:43 |
| S8 | 1149  | (generate generated generation generating) and (compare comparator compared comparison comparing) and ((test TESTING TESTER TESTED) with ((integrated adj circuit) circuit semiconductor ic memory logic)) and (expect\$ with result) and (fail failure failed failing error erroneous) and "714"/\$.ccls.                    | US-PGPUB;<br>USPAT;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2006/01/10 08:43 |
| S9 | 545   | (generate generated generation generating) and (compare comparator compared comparison comparing) and ((test TESTING TESTER TESTED) with ((integrated adj circuit) circuit semiconductor ic memory logic)) and (expect\$ with result) and (fail failure failed failing error erroneous) and "714"/\$.ccls. and (range window) | US-PGPUB;<br>USPAT;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2006/01/11 09:36 |